

JAN 31 2006

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Appl. No.: 10/695,336

Applicant(s): Geiss et al.

Filed.: October 28, 2003

Art Unit: 2813

Dkt. No.: BUR920010184US2

Examiner: Heather Anne Doty

Title: **METHOD OF CONTROLLING GRAIN SIZE IN A POLYSILICON LAYER AND
IN SEMICONDUCTOR DEVICES HAVING POLYSILICON STRUCTURES**

PETITION UNDER 35 USC 1.136(a)

Commissioner for Patents & Trademarks
P. O. Box 1450
Alexandria, VA 22313-1450

Applicants hereby petition for a two month extension of time for responding to the final office action of September 14, 2005. The Director is hereby authorized to charge Deposit Account 09-0456 for the fee required under 35 USC 1.17(a).

Respectfully submitted,
FOR: Geiss et al.

Dated: 01/31/2006

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